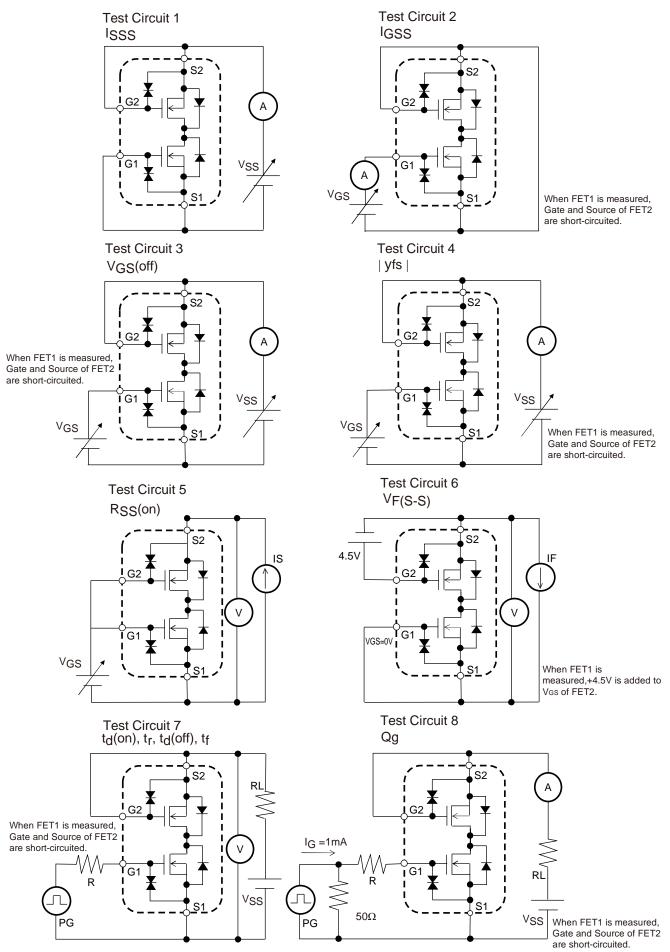
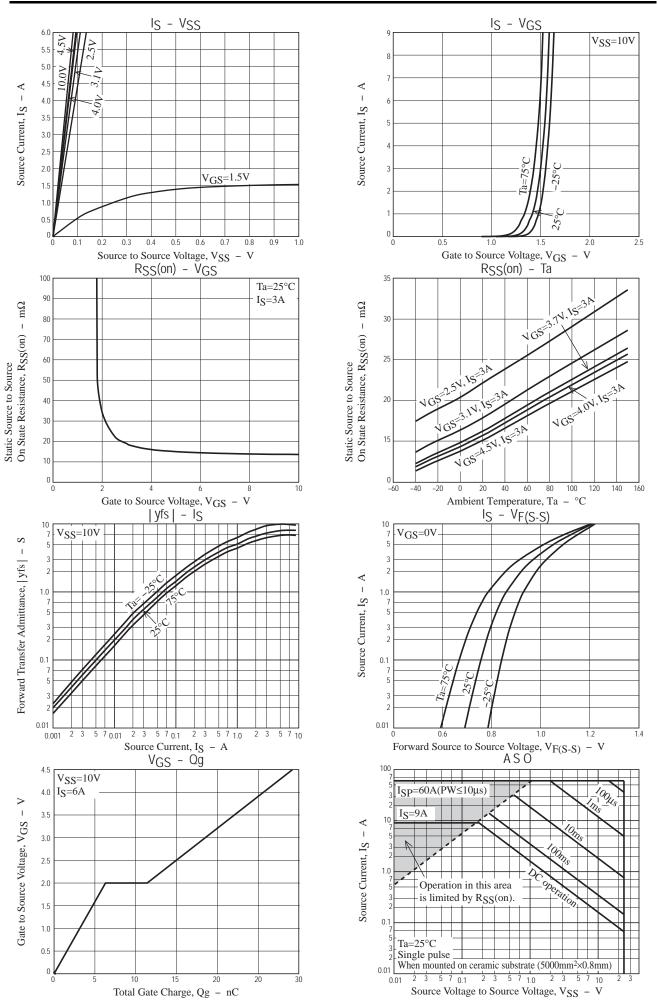
### **Electrical Characteristics** at $Ta = 25^{\circ}C$

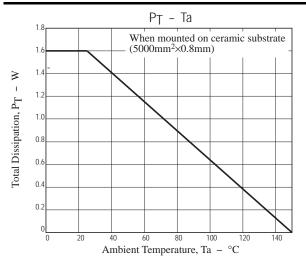
| 5  | Symbol                | <b>2</b>   |                    | Ratings |       |      |    |
|--|-----------------------|--|--------------------|---------|-------|------|----|
| Parameter                                      |                       | Conditi  | min                | typ     | max   | Unit |    |
| Source to Source Breakdown Voltage             | V(BR)SSS              | I <sub>S</sub> =1mA, V <sub>GS</sub> =0V                                       | Test Circuit 1     | 24      |       |      | V  |
| Zero-Gate Voltage Source Current               | ISSS                  | V <sub>SS</sub> =20V, V <sub>GS</sub> =0V                                      | Test Circuit 1     |         |       | 1    | μA |
| Gate to Source Leakage Current                 | IGSS                  | V <sub>GS</sub> =±8V, V <sub>SS</sub> =0V                                      | Test Circuit 2     |         |       | ±1   | μA |
| Cutoff Voltage                                 | VGS(off)              | V <sub>SS</sub> =10V, I <sub>S</sub> =1mA                                      | Test Circuit 3     | 0.5     |       | 1.3  | V  |
| Forward Transfer Admittance                    | yfs                   | V <sub>SS</sub> =10V, I <sub>S</sub> =3A                                       | Test Circuit 4     |         | 7.3   |      | S  |
| Static Source to Source On-State<br>Resistance | R <sub>SS</sub> (on)1 | IS=3A, VGS=4.5V  | Test Circuit 5     | 10.8    | 15.5  | 18   | mΩ |
|  | R <sub>SS</sub> (on)2 | IS=3A, VGS=4.0V  | Test Circuit 5     | 11.1    | 16    | 19   | mΩ |
|  | R <sub>SS</sub> (on)3 | IS=3A, VGS=3.7V  | Test Circuit 5     | 11.5    | 16.5  | 20   | mΩ |
|  | R <sub>SS</sub> (on)4 | I <sub>S</sub> =3A, V <sub>GS</sub> =3.1V                                      | Test Circuit 5     | 12.5    | 18    | 23.5 | mΩ |
|  | R <sub>SS</sub> (on)5 | IS=3A, VGS=2.5V  | Test Circuit 5     | 14.9    | 23    | 30   | mΩ |
| Turn-ON Delay Time                             | t <sub>d</sub> (on)   |  |                    |         | 340   |      | ns |
| Rise Time                                      | tr                    | V <sub>SS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>S</sub> =3A Test Circuit 7 |                    |         | 600   |      | ns |
| Turn-OFF Delay Time                            | t <sub>d</sub> (off)  |  |                    |         | 26000 |      | ns |
| Fall Time                                      | tf                    |  |                    |         | 28000 |      | ns |
| Total Gate Charge                              | Qg                    | V <sub>SS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>S</sub>                    | =9A Test Circuit 8 |         | 29    |      | nC |
| Forward Source to Source Voltage               | VF(S-S)               | IS=3A, VGS=0V  | Test Circuit 6     |         | 0.77  | 1.2  | V  |

# EFC4621R

## Test circuits are example of measuring FET1 side



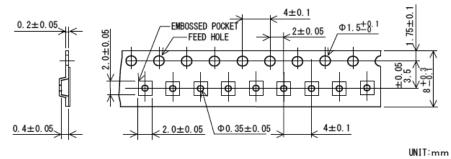




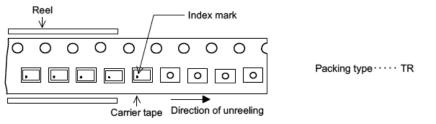
### **Taping Specification** EFC4621R-TR

#### 1. Taping Configuration

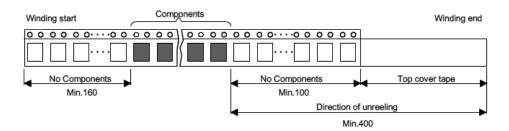
1-1.Carrier Tape Size (unit:mm)



1-2. Device Placement Direction



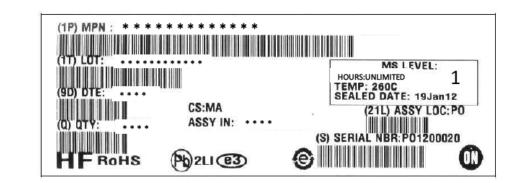
#### 1-3 .Leader portion and Trailer portion (unit:mm)



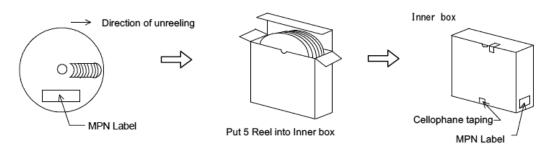
Packing Format

| Carrier Tape code | Package code     | Maximum Number of devices contained. (pcs.) |           | Packing Format |  |  |
|-------------------|------------------|---|-----------|----------------|--|--|
|                   |                  | Reel  | Inner box |                | Inner box BOX(C-1)                               |  |
| 2020X04           | EFCP1818-4CE-022 | 5,000                                       | 25,000    |                | 5reels contained.<br>Dimensions:mm<br>183×72×185 |  |

MPN Label

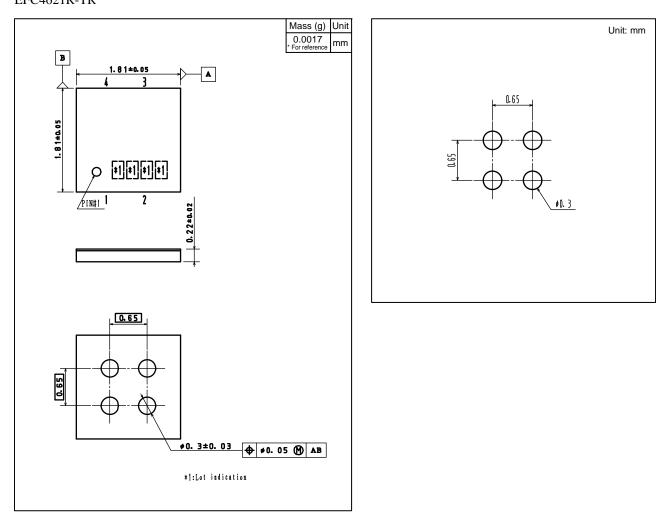


Packing Method



Land Pattern Example

### Outline Drawing EFC4621R-TR



Note on usage : Since the EFC4621R is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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